PCN Number: 20140408002 PCN Date: 04/15/2014							
Title: Qualification of TI Malaysia as Additional Assembly/Test Site for Select Devices							
Customer Contact:PCN ManagerPhone:+1(214)480-6037Dept:Quality Services							
Proposed 1st Ship Date:07/15/2014Estimated Sample Availability:Date Provided at Sample request							
Change Type:							
Assembly Site Design Wafer Bump Site							
Assembly Process Data Sheet Wafer Bump Material							
Assembly Materials Mechanical Specificati		Part number change Test Site	╎┝┥	Wafer B Wafer F	ump Process		
Packing/Shipping/Lab		est Process	╎┝┤				
		00000	Wafer Fab Materials Wafer Fab Process				
		PCN Details					
Description of Change:							
Qualification of TI Malaysia as Additional Assembly/Test Site for Select Devices. Material differences are as follows:							
• Group 1 – Devices		e Mold Compound cha	nge	only			
	MEX	MLA					
Mold Compound 4	205694, 421188	0 4209640					
 Group 2 – No material differences Test coverage, insertions, conditions will remain consistent with current testing and verified with 							
test MQ.							
Reason for Change: Continuity of Supply							
	rm Fit Fund	tion Quality or Peliab	ilitv	(positive	a / negative):		
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative): None							
Changes to product identification resulting from this PCN:							
Assembly Site TI Mexico	Assembly Site Origin (22L) ASO: MEX						
TI Taiwan	Assembly Site Origin (22L) ASO: MLX Assembly Site Origin (22L) ASO: TAI						
TI Malaysia	Assembly Site Origin (22L) ASO: MLA						
Sample product shipping label (not actual product label) TEXAS INSTRUMENTS MADE IN: Malaysia 20: MSL 2 /260C/1 YEAR SEAL DT 03/29/04 OPT: ITEM: 39 BL: 5A (L)T0:1750 (not actual product label) (1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY (1T) 7523483S12 (P) (2P) REV: (V) 0033317 (20L) CS0: SHE (21L) CC0:USA (2L) AS0: MLA (23L) AC0: MYS							
ASSEMBLY SITE CODES: TI-Mexico = M, TI-Taiwan = T, TI-Malaysia = K							

Product Affected: Group 1					
SN1106046D	TPS5402DR	TPS5403DR	TPS5405DR		
SN1106046DR					
Product Affected: G	oup 2				
HPA00836PWPR	TPA3020D2PWPR	TPA3111D1PWPR	TPA3113D2PWP		
HPA00928PWPR	TPA3110D2PWP	TPA3112D1PWP	TPA3113D2PWPR		
HPA01070PWPR	TPA3110D2PWPR	TPA3112D1PWPR			
HPA01071PWPR	TPA3110LD2PWPR	TPA3112SD1PWP			
TPA3020D2PWP	TPA3111D1PWP	TPA3112SD1PWPR			

	Group 1	: Qualifie	cation Data				
This qualification has been specific validates that the proposed changes of th						alification o	lata
Qual Vehicle : TPS5405D (MSL1-260C)							
Package Construction Details							
Assembly Site:	MLA				oound: 4209640		
# Pins-Designator, Family:	8-D, SOIC Mount Com		Mount Comp	pound: 4042500			
Lead Finish, Base	NiPdAu, Cu		Bond Wire:		0.	0.96 Mil Dia. Cu	
Qualification: 🗌 Plan 🛛 Test Results							
Reliability Test		Conditions		S	am	nple Size /	' Fail
Reliability Test		Conditions		Lot 1		Lot 2	Lot3
Electrical Characterization		-		30/0		-	-
Manufacturability Qualification	(MQ)			Pass		-	-
**High Temp Storage Bake		170C (420		77/0		77/0	77/0
**Temp Cycle		-65C/150C (500 Cycles)		77/0		77/0	77/0
Moisture Sensitivity		L1-260C				12/0	12/0
**- Preconditioning sequence: Level 1-260C.							
	Group 2	: Qualifio	cation Data				
Qual Vehicle 1 : SN89062PWP (MSL2-260C)							
Package Construction Details							
Assembly Site:	MLA		Mold Compound:		42	4205443	
<pre># Pins-Designator, Family:</pre>	24-PWP, HTSSOP		Mount Compound:		4208458		
Lead Finish, Base	NiPdAu, Cu		Bond Wire:		1.30 Mil Dia. Cu		
Qualification: 🗌 Plan	🛛 Test Res	ults					
Reliability Test		Conditions		Sample Size			' Fail
				Lot 1		Lot 2	Lot3
**Life test		125C (1000 hrs)		77/0		-	-
**Biased HAST		130C/85%RH (96 hrs)		77/0		77/0	77/0
**Autoclave		121C, 2atm (96 hrs)		77/0		77/0	77/0
**High Temp Storage Bake		150C (1000 hrs)		77/0		77/0	77/0
**Temp Cycle		-65C/150C (500 Cycles)		77/0		77/0	77/0
**Thermal Shock		-65C/150C (500 Cycles)		77/0		77/0	77/0
Manufacturability Qualification (MQ)				Pass		-	-
Moisture Sensitivity		L2-260C		12/0		12/0	12/0
**- Preconditioning sequence:	Level 2-260)C.					

Qual Vehicle 2 : SN84001PWP (MSL2-260C)						
Package Construction Details						
Assembly Site:	MLA		Mold Compound:		4205443	
# Pins-Designator, Family:	28-PWP, HTSSOP		Mount Compound:		4208458	
Lead Finish, Base	NiPdAu, Cu		Bond Wire:		0.96 Mil Dia. Cu	
Qualification: 🗌 Plan 🛛 Test Results						
Reliability Test		Conditions		Sample Size / Fail		
**Life test		125C (1000 hrs)		77/0		
**Biased Temp and Humidity		85C/85%RH (1000 hrs)		77/0		
**Autoclave		121C, 2atm (96 hrs)		77/0		
**High Temp Storage Bake		170C (420 hrs)		77/0		
**Temp Cycle		-65C/150C (500 Cycles)			77/0	
Manufacturability Qualification (MQ)					Pass	
**- Preconditioning sequence: Level 2-260C.						

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com